

то :				文件编号	HXA-L36-24(01)			
10 ·				发行日期	2015年11月15日			
		承	认规格	各 书				
			E: Power					
		系列号	+: <u>HXNR403</u>	OB-Series				
		客户料号	<u> </u>					
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	承认	人日期	年	月	日			
	(于	贵司承认后请签	这 署一份返回华	信安电子,谢谢	4:)			
	厦	门华信安电	子科技有限公	公司技术质量	重部			
			T	1	-			
		承认	确认	作成				
		龙梅	梁峰	王亮				
		TEL: 0592-6	301603 FAX :	: 0592-5205265				
	Http://www.xmisnd.com							

Power Inductor

HXNR4030B-SERIES

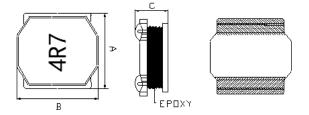
		ECN HISTORY	LIST		
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	15/11/15	新發行	龙梅	梁峰	王亮
備註					

Power Inductor

1. Features

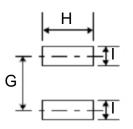
- 1. This specification applies Low Profile Pow er Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension





HXNR4030B-SERIES



Series	A(mm)	B(mm)	C(mm)	G(mm)	H(mm)	l(mm)
HXNR4030B	4.0±0.2	4.0±0.2	3.0 max.	2.8 ref.	3.7 ref.	1.2 ref.

Units: mm

3. Part Numbering

HXNR	4030	B	-	2R2	Μ
А	в	С		D	Е
A: Series					
B: Dimension					
C: Control S/N					

- D: Inductance
- E: Inductance Tolerance

2R2=2.2uH M=±20%;Y=±30%

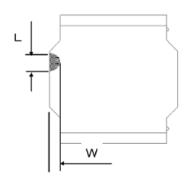
4. Specification

ISND Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	SRF (MHz) min.	DCR (Ω) ±30%	l sat (A)	Irms (A)
HXNR4030B-1R0Y	1.0	±30%	1V100K	90	0.025	4.70	3.35
HXNR4030B-1R5Y	1.5	±30%	1V100K	90	0.030	4.55	3.20
HXNR4030B-2R2M	2.2	±20%	1V100K	60	0.038	4.40	2.95
HXNR4030B-3R3M	3.3	±20%	1V100K	45	0.052	3.30	2.40
HXNR4030B-4R7M	4.7	±20%	1V100K	35	0.065	2.90	2.00
HXNR4030B-6R8M	6.8	±20%	1V100K	30	0.095	2.65	1.60
HXNR4030B-100M	10	±20%	1V100K	25	0.110	1.95	1.50
HXNR4030B-150M	15	±20%	1V100K	18	0.198	1.65	1.20
HXNR4030B-220M	22	±20%	1V100K	15	0.270	1.30	1.00
HXNR4030B-330M	33	±20%	1V100K	12	0.420	1.00	0.81
HXNR4030B-470M	47	±20%	1V100K	8	0.430	0.93	0.72
HXNR4030B-680M	68	±20%	1V100K	5	0.930	0.80	0.42

Note:

 $\label{eq:lsat:Based on inductance change $$($\alpha L/L0 : $\leq -30\% $) @ ambient temp. 25°C$$ Irms: Based on temperature rise $$($\alpha T : 40°C $ typ. $)$$$

Core chipping

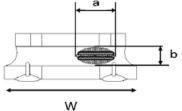


Туре	L	w	
HXNR4030B	1.5mm Max.	1.5mm Max.	

Void appearance tolerance Limit

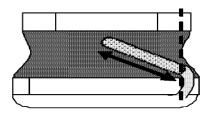
Size of voids occurring to coating resin is specified below.

The appearance standard of the chipping size in top side, of bottom side ferrite core is following dimension.



External appearance criterion for exposed wire

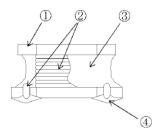
Exposed end of the winding wire at the secondary side should be 2mm and below.



Exposed wire tolerance limit of coating resin part on product side. Size of exposed wire occurring to coating resin is specified below.

- 1. Width direction (dimension a): Acceptable when a \leq w/2 Nonconforming when a > w/2
- 2. Length direction (dimension b): Dimension b is not specified.
- 3. When total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, that is acceptable.

5. Material List



No.	ltem	Material
1	Core	Ni-Zn ferrite
2	Wire	Copper Wire
3	Coating	Ероху
4	Solder	Lead free

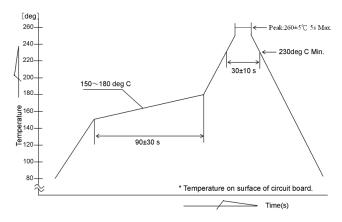
6. Reliability and Test Condition

ltem	Performance		Test Method and R	emarks	
Operating Temperature	- 25 ~ +125 [°] C.	Including self-	generated heat		
Storage Temperature	-40 ~ +85℃. -5 to 40℃ for the product with taping.				
Rated current					
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 1V			
DC Resistance		DC Ohmmeter:	: HIOKI3227 or equiva	lent	
Temperature characteristics	Inductance change : Within±20%	Measurement of inductance shall be taken at tempera rang within-25°C to +85°C. With reference to inductance value at+20 °C,change is shall be calculated. Measurement of inductance shall be taken at tempera rang within-40°C to +125°C. With reference to inductance value at+20 °C,change is shall be calculated.			ate ure
Resistance to flexure substrate	No damage.	The test samp the reflow. As illustrated b indicating until Rose Rose Rose Rose Rose Rose Rose Rose	bles shall be soldered below, applyforce in th deflection of the test l below in the set l below in th	e direction of the aboard reaches to 2	arrow
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board a by the reflow. 10 N, 5 s Applied force : 10 N to X and Y directions. Duration : 5s Solder cream thickness : 0.15			l and
Resistance to Vibration	Inductance change : Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by treflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time : 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement wit 48hrs.			I
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immerse in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: 245±5°C Time: 5±1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.			
Resistance to soldering	Inductance change : Within±10% No abnormality observed in appearance.	The test sample shall be exposed to reflow oven at 230±5 for 40 seconds, with peak temperature at 260±5℃ for 5 seconds,2 times. Test board thickness: 1.0mm Test board material: glass epoxy-resin			
Thermal shock	Inductance change : Within±10% No abnormality observed in appearance.				ure n

ISND

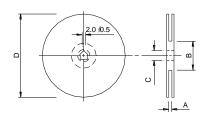
ISND	P5
Damp heat life test	Test Method and Remarks The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in ther mostatic oven set at specified temperature and humidity as shown in below. Temperature: 60+2℃ Humidity: 90-95%RH Time: 500+24/-0 hrs
Loading under damp heat life test	The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in ther mostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below. Temperature: 60±2°C Humidity: 90–95%RH Applied current: Rated current Time: 500+24/-0 hrs
Low temperature life test	The test samples shall be soldered to the test board by the reflow. After that, the test samples shall be placed at test conditions as shown in below. Temperature:-40±2°C Time:500+24/-0 hrs
Loading at high temperature life test	The test samples shall be soldered to the test board by the reflow. Temperature: 85±2°C. Applied current: Rated current Time: 500+24/-0 hrs.

7. Soldering



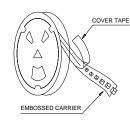
8. Packaging Information

(1) Reel Dimension



A(mm)

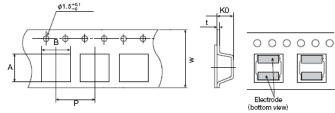
12.4±2.0



D(mm)

330±2.0





Туре	A(mm)	B(mm)	Ko(mm)	P(mm)	W(mm)	t(mm)
HXNR4030B	4.25±0.1	4.25±0.1	3.25±0.1	8.0±0.1	12±0.3	0.4±0.05

(3) Packaging Quantity

Туре

HXNR4030B

Туре	Chip / Reel
HXNR4030B	2000

B(mm)

100±4.0

C(mm)

13.2±0.2

Application Notice

Storage Conditions

To maintain the solderability of terminal electrodes:

1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.

2. Temperature and humidity conditions: Less than 40 $^\circ\!{\rm C}$ and 60% RH.

3. Recommended products should be used within 12 months form the time of delivery.

4. The packaging material should be kept where no chlorine or sulf ur exists in the air.

Transportation

1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.

2. The use of tweezers or vacuum pick up is strongly recommended for individual components.

3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)